

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/613,738	MCAULAY, ALASTAIR D.	
Examiner John Juba, Jr.		Art Unit 2872	Page 1 of 2	

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-2001/0051856 A1	12-2001	Niu et al.	702/57
	C	US-			
	D	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	U	E.N. Glytsis, et al., "Rigorous three-dimensional coupled-wave diffraction analysis of single and cascaded anisotropic gratings", J. Opt. Soc. Amer. A, Vol. 4, No.11, pp. 2061-2080, November 1987.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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